

interfacial layer width, σ_s

in thin films

The characteristic length defined by the variance of the Gaussian function fitted to the gradient of the electron density profile established by X-ray specular reflectivity studies of the liquid interface.

Source:

PAC, 1994, 66, 1667 (*Thin films including layers: terminology in relation to their preparation and characterization (IUPAC Recommendations 1994)*) on page 1674